



Title of Change:	PQ ETS800 Test Enablement at UTAC Thai Limited, Thailand (UTL) for NCP81610MNTXG and NCP81611MNTXG.										
Proposed first ship date:	29 August 2019										
Contact information:	Contact your local ON Semiconductor Sales Office or <Elmer.Milar@onsemi.com>										
Samples:	Contact your local ON Semiconductor Sales Office or <PCN.samples@onsemi.com> Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.										
Additional Reliability Data:	Test Qual Only. No Reliability performed.										
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>										
Change Part Identification:	None. Affected products tested between sites will be traceable by date codes.										
Change Category:	<input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input checked="" type="checkbox"/> Test Change <input type="checkbox"/> Other _____										
Change Sub-Category(s):	<input checked="" type="checkbox"/> Manufacturing Site Addition <input type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Site Transfer <input type="checkbox"/> Product specific change <input checked="" type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____										
Sites Affected:	ON Semiconductor Sites: ON Carmona, Philippines	External Foundry/Subcon Sites: UTAC									
Description and Purpose:											
	<table border="1"> <thead> <tr> <th></th> <th>Before Change Description</th> <th>After Change Description</th> </tr> </thead> <tbody> <tr> <td>Location</td> <td>ON Semiconductor, Carmona, Philippines (OSPI)</td> <td> Final Test will be done in two locations : 1. ON Semiconductor, Carmona (OSPI) 2. UTAC Thai Limited, Thailand (UTL) </td> </tr> <tr> <td>Test Equipment</td> <td> ON Semiconductor, Carmona Philippines (OSPI) only : Teradyne ETS800 Tester + Multitest MT2168 handler </td> <td> ON Semiconductor, Carmona Philippines (OSPI) and UTAC Thai Limited, Thailand (UTL) : Teradyne ETS800 Tester + Multitest MT2168 handler (Same equipment sets) </td> </tr> </tbody> </table>			Before Change Description	After Change Description	Location	ON Semiconductor, Carmona, Philippines (OSPI)	Final Test will be done in two locations : 1. ON Semiconductor, Carmona (OSPI) 2. UTAC Thai Limited, Thailand (UTL)	Test Equipment	ON Semiconductor, Carmona Philippines (OSPI) only : Teradyne ETS800 Tester + Multitest MT2168 handler	ON Semiconductor, Carmona Philippines (OSPI) and UTAC Thai Limited, Thailand (UTL) : Teradyne ETS800 Tester + Multitest MT2168 handler (Same equipment sets)
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There are no product material as a result of this change. There is no product marking change as a result of this change.											

**Reliability Data Summary:**

Qualification Items / Steps	Quality characteristic / Response to be Monitored (Input, in-process, Output)	Test Condition	Sample Size	Accept Criteria / Result
Correlation Study	All Final Test Parameters	25C	10units / OPN	All Parameters < 10% shift PASSED
Key Parameter Electrical Distribution Comparison (OSPI & UTL)	Cpk Comparison	25C	3/1 lots QV/BS 3kunits / lot	Comparable
Reject Bin Analysis	Reject BIN count / BIN category	25C	1 lot / OPN 1k / lot	Equal
Test (Yield, GDPW, Correlation, etc)	FT Yield	25C	3/1 lots QV/BS 3kunits / lot	>95% / PASSED
Electrical QA	QC Yield	25C	2 lots / 3kunits 2 lots / 490units	100%

Electrical Characteristic Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

Part Number	Qualification Vehicle
NCP81610MNTXG	NCP81610
NCP81611MNTXG	NCP81610